

**IN THE SPECIFICATION****Amendments to the Specification:**

Please amend the following at page 1, lines 7-12 of the specification:

The present invention relates to a method and a device for inspecting a secondary battery precursor, and further to a method for manufacturing a secondary battery. The present invention particularly relates to, for example, a non-destructive inspection for detecting a secondary battery precursor with insufficient isolation insulation between electrodes from a plurality of manufactured secondary battery precursors.

Please amend the following at page 12, lines 27-34 of the specification:

FIG. 5 shows an exemplary relationship between the reference waveform and a reference current value 13, 14. In the example shown in FIG. 5, [[a]] reference value 14 also is set below the reference waveform based on the reference waveform. When a current value lower than the reference value 14 is detected, there is a need to consider the possibility of a failure of the inspection itself. An abnormally low current value is obtained due to poor electrical contact between the terminals of the inspection device and an electrode body, for example.

Please amend the following at page 13, lines 11-21 of the specification:

It is not necessarily required that the value for comparison is set based on the charging current waveform obtained from a non-defective product. As shown in FIG. 4, for example, it is possible to determine that the abnormal current is detected when a current value exceeding a previously set predetermined value ( $I_1$ ) is measured in a predetermined time period ( $T_2-T_1$ ) within the range between starting of the application of the voltage and obtaining of a constant current value. Instead of the predetermined value ( $I_1$ ), a value ( $I_T$ ) set as a function of time may be used as the reference value. Although

this inspection method has a lower accuracy than that of the method using the charging current waveform, it can be performed easily when the charging current waveform of the non-defective product can be estimated.